

**INFORMATION DISCLOSURE STATEMENT BY APPLICANT**  
 (Use several sheets if necessary)
Atty. Docket No.  
1391-44200Serial No.  
10/743,508Applicant  
Guoyu (David) HuFiling Date  
Dec. 22, 2003Group  
2862**REFERENCE DESIGNATION U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE

**FOREIGN PATENT DOCUMENTS**

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	Translation YES NO

**OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

TJ	AA	David P. Shattuck et al; Scale Modelling of the Laterolog Using Synthetic Focusing Methods; <i>The Log Analyst</i> July-August 1987; (pp. 357-369)
TJ	AB	SPE 89 <sup>TH</sup> Annual Technical Conference (SEP 28425); <i>Invasion Profiling With a Multiple Depth of Investigation Electromagnetic Wave Resistivity Sensor</i> ; M. S. Bittar et al; 25-28 Sept. 1994; (pp. 1-23)

EXAMINER

Tyrone Gasher

DATE CONSIDERED

8/3/05

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP §609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.